Test Report issued under the responsibility of:





TEST REPORT EN 60947-2				
Low-voltage switchgear and controlgear - Part 2: Circuit-breakers				
	要设备			
Report Reference No.	. 00901-CE2015CQ09803-007245			
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CB Testing Laboratory	Shanghai Testing Michaeltion Instruct for Electrical Equipment (STIEE)			
Address	. 505 Wu Ning Rd. Shanghai 209063, P.R. CHINA			
Applicant's name	Zhejiang Tengen Electrics Co., Ltd.			
Address	TENGEN Industry Zone, Liushi, Yueqing, Zhejiang, P.R.China			
Test specification:				
Standard	. EN 60947-2:2006 (Fourth Edition) + A1: 2009 + A2: 2013			
Test procedure	CCA scheme			
Non-standard test method	N/A			
Test Report Form No.	. EN60947_2G			
Test Report Form(s) Originator DEKRA Certification BV				
Master TRF	. Dated 2013-11			
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a CB Test Certificate issued by an NCB in accordance with IECEE 02.				
Test item description				
Trade Mark				
	. Zhejiang Tengen Electrics Co., Ltd.			
Model/Type reference				
Ratings	Ue:AC415V, AC690V; In:200A,250A,400A,500A,630A,800A,1000A,1250A,1600A,1900A,2000A			

Testing procedure and testing location:				
\mathbf{X}	CB Testing Laboratory:	Shanghai Testing & Inspection Institute for Electrical Equipment (STIEE)		
Testing location/ address		505 Wu Ning Rd. Shanghai 200063, P.R. CHINA		
Tested by (name + signature):		Cheng Yanmin	程序教	
	Approved by (name + signature):	Wei Qingyuan	程序数 魏沃媛	
	Testing procedure: TMP	N/A		
Testing location/ address:		N/A		
	Tested by (name + signature):	N/A		
Approved by (name + signature):		N/A		
Testing procedure: WMT		N/A		
Testing location/ address:		N/A		
Tested by (name + signature):		N/A		
Witnessed by (name + signature):		N/A		
	Approved by (name + signature):	N/A		
	Testing procedure: SMT	N/A		
Testing location/ address:		N/A		
Tested by (name + signature):		N/A		
Approved by (name + signature):		N/A		
Supervised by (name + signature):		N/A		